Supplementary Information

Impact of grain sizes on optoelectronic performances of 2D Ruddlesden-Popper perovskite-based photodetectors

Bohee Hwang, Youngjun Park, and Jang-Sik Lee*

Department of Materials Science and Engineering. Pohang University of Science and Technology (POSTECH), Pohang 37673, Korea

*Corresponding Author. E-mail: jangsik@postech.ac.kr



Fig. S1. X-ray diffraction patterns of the BA₂MAPb₂I₇ films that were cast from $P_{\text{DMSO}} = 0$, 0.3, 0.5, 0.7, and 1.

BA2MAPb2I7	
SiO ₂	
Si	100 nm

Fig. S2. Cross-sectional SEM image of the perovskite film that was formed using $P_{\text{DMSO}} = 1$.



Fig. S3. Atomic force microscopy (AFM) images of the films that were cast from (a) $P_{DMSO} = 0$, (b) $P_{DMSO} = 0.3$, (c) $P_{DMSO} = 0.5$, (d) $P_{DMSO} = 0.7$, and (e) $P_{DMSO} = 1$.



Fig. S4. Schematic illustration and optical image of fabricated photodetector device, and the structure of $BA_2MAPb_2I_7$ (atom colors: Pb = yellow; I = purple; C = black; N = green; H = blue).



Fig. S5. (a) *I-V* characteristics of the photodetectors based on $P_{\text{DMSO}} = 0, 0.3, 0.5, 0.7, \text{ and } 1$ in darkness.



Fig. S6. Photoswitching characteristic at a bias of 5 V.



Fig. S7. EQE values according to light intensities.